

<b>Notice of References Cited</b>	Application/Control No. 10/521,052	Applicant(s)/Patent Under Reexamination WIESE ET AL.	
	Examiner David Q. Nguyen	Art Unit 2617	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,218,367	06-1993	Sheffer et al.	342/457
*	B	US-2004/0204806	10-2004	Chen et al.	701/036
*	C	US-5,218,367	06-1993	Sheffer et al.	342/457
*	D	US-2004/0113768	06-2004	Rodgers, Stephen Fredrick	340/506
*	E	US-6,184,801	02-2001	Janky, James M.	340/988
*	F	US-6,100,792	08-2000	Ogino et al.	340/426.25
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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